

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/824,111	BAEK ET AL.	
	<b>Examiner</b> Luan Thai	<b>Art Unit</b> 2891	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
All above		8/17/2007	LT